Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10530797	BUSCHKE ET AL.
Examiner	Art Unit
Washburn, Douglas N	2863

SEARCHED

Class	Subclass	Date	Examiner
73	1.82	03/08/2007	DNW
73	570	03/08/2007	DNW
73	584	03/08/2007	DNW
73	598	03/08/2007	DNW
73	600	03/08/2007	DNW
702	35	03/08/2007	DNW
702	39	03/08/2007	DNW
702	103	03/08/2007	DNW
702	159	03/08/2007	DNW
702	171	03/08/2007	DNW
702	35	04/22/2008	DW
702	39	04/22/2008	DW
702	171	04/22/2008	DW

SEARCH NOTES

Search Notes	Date	Examiner
Inventor name search - see printout - (USPGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM-TDB)	03/08/2007	DNW
EAST keyword/keyphrase - see printout - (USPGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM-TDB)	03/08/2007	DNW
IEEE keyword/keyphrase - see printout	03/08/2007	DNW
G01N29/00 - see printout - (USPGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM-TDB)	03/08/2007	DNW
G01H17/00 - see printout - (USPGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM-TDB)	03/08/2007	DNW
G06F11/30 - see printout - (USPGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM-TDB)	03/08/2007	DNW
G06F15/00 - see printout - (USPGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM-TDB)	03/08/2007	DNW
G06F19/00 - see printout - (USPGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM-TDB)	03/08/2007	DNW
73/1.82, 570, 584, 597, 598, 599, 600, 602 - see printout - (USPGPUB; USPAT; USOCR)	03/08/2007	DNW
702/33, 35, 39, 81, 103, 159, 171, 183 - see printout - (USPGPUB; USPAT; USOCR)	03/08/2007	DNW
Inventor name search - update - see printout - (USPGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM-TDB)	04/22/2008	DW
EAST keyword/keyphrase - update - see printout - (USPGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM-TDB)	04/23/2008	DW

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Search Notes	Date	Examiner
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EPO; JPO; DERWENT; IBM-TDB)		
702/35, 39, 171 - update - see printout - (USPGPUB; USPAT; USOCR)	04/22/2008	DW

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